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Sheet 3 of 6

Complete if Known

Application No.	10/661,037
Filing Date	September 12, 2003
First Named Inventor	John D. Hyde
Art Unit	2822
Examiner Name	Ida M. Soward

Attorney Docket Number 22524-17802

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document No.	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
Change(s) applied to document, /A.J.P./ 12/23/2011	A61	US-4,816,883	03-28-1989	Baldi
	A62	US-4,653,928	03-31-1987	Anderson et al. 4,653,928
	A63	US-4,622,656	11-11-1986	Kamiya
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	A65	US-4,420,871	12-20-1983	Scheibe
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Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ² – Number ³ Kind Code ⁴ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	T ⁵
	B1	JP 2005-533372	11-04-2005	Impinj, Inc.	
	B2	JP 29-51605	03-10-1998	Programmable Microelectron Co.	
	B3	EP 0 562 257 A1	09-29-1993	International Business Machines Corporation	
	B4	WO 00/60672 A1	10-12-2000	Koninklijke Philips Electronics N.V.	
	B5	WO 00/38239 A1	06-29-2000	Lattice Semiconductor Corporation	

OTHER REFERENCES – NON-PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T ⁶
	C1	ANDREOU, AG. et al., "Neural information processing II," in M. Ismail and T. Fiez, eds., Analog VLSI Signal and Information Process, New York: McGraw-Hill, Inc., pp. 358-413, 1994.	
	C2	ARITOME, S. et al., "Reliability Issues of Flash Memory Cells," Proceedings of the IEEE, May 1993, pp. 776-787, Vol. 81, No. 5.	
	C3	BARAFF, G.A., "Distribution Functions and Ionization Rates for Hot Electrons in Semiconductors," Short-Range Order Effect on Magnetic Anisotropy, Physical Review, December 15, 1962, pp. 2507-2517, Vol. 128, No. 6.	
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Examiner Signature	/Ida Soward/	Date Considered	03/27/2011
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